

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Kelly T. Hurley

Serial No.: Unknown

Filed: Concurrently herewith

For: FLASH FLOATING GATE USING  
EPITAXIAL GROWTH

§  
§ Group Art Unit: Unknown  
§  
§ Examiner: Unknown  
§  
§ Atty. Docket: 2000-0133.00  
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JC903 U.S. PTO  
09/905584

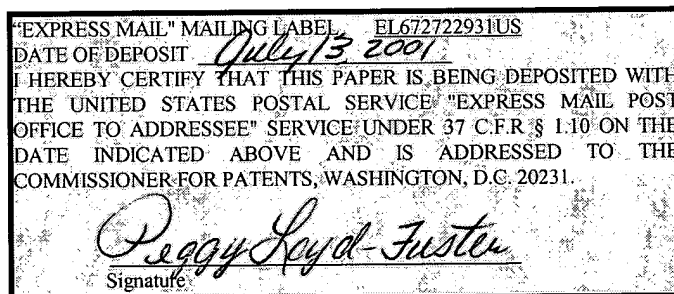


*SSB*  
*072*  
*1-16-02*

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
Washington, D.C. 20231

Dear Sir:



In compliance with the duty of disclosure under 37 C.F.R. § 1.56, Applicant respectfully requests that this Information Disclosure Statement be entered and that the references listed on the attached Form PTO-1449 be considered by the Examiner and made of record. Copies of the listed references are enclosed for the convenience of the Examiner.

In accordance with 37 C.F.R. § 1.97(b), this Information Disclosure Statement is not to be construed as a representation that a search has been made or that no other possible material information as defined in 37 C.F.R. § 1.56(a) exists.

The following references are submitted for the Examiner's review:

U.S. Patents

<u>U.S. Patent No.</u>	<u>Issue Date</u>	<u>Inventor</u>
5,210,047	May 11, 1993	Woo et al.

Articles

"Novel 0.44 $\mu$ m<sup>2</sup> Ti-Salicide STI Cell Technology for High Density NOR Flash Memories and High Performance Embedded Application", H. Watanabe et al., IEDM 98, pp. 975-978

"A 130-mm<sup>2</sup>, 256-Mbit NAND Flash with Shallow Trench Isolation Technology", Kenichi Imamiya et al., IEEE Journal of Solid-State Circuits, Vol. 34, No. 11, November 1999

As this information is being submitted within three months of the date of filing of the application, Applicant understands that no fee or certification is required for the submission and consideration of this information at this time.

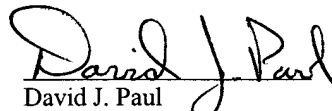
If there are any matters which may be resolved or clarified through telephone interview, the Examiner is respectfully requested to contact Applicant's undersigned attorney at the number indicated.

\* \* \* \*

A Form PTO-1449 is enclosed herewith.

Respectfully submitted,

Date: 7/13/2001



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FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: 2000-0133.00	Serial No: Unknown
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (37 CFR 1.98(b)) <i>(use several sheets if necessary)</i>		Applicant: Kelly T. Hurley	
		Filing Date: Concurrently Herewith	Group: Unknown

PTO  
09/905584  
07/13/01

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	
AA	5,210,047	May/ 93	Woo et al.	437	43	
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
AL						<input type="checkbox"/>	<input type="checkbox"/>
AM						<input type="checkbox"/>	<input type="checkbox"/>
AN						<input type="checkbox"/>	<input type="checkbox"/>
AO						<input type="checkbox"/>	<input type="checkbox"/>
AP						<input type="checkbox"/>	<input type="checkbox"/>
AQ						<input type="checkbox"/>	<input type="checkbox"/>

Initial

OTHER ART (including author, title, date, pertinent pages, etc.)

AR		"Novel 0.44 $\mu$ m <sup>2</sup> Ti-Salicide STI Cell Technology for High Density NOR Flash Memories and High Performance Embedded Application", H. Watanabe et al., IEDM, 98 pp. 975-978
AS		"A 130-mm <sup>2</sup> , 256-Mbit NAND Flash with Shallow Trench Isolation Technology", Kenichi Imamiya et al., IEEE Journal of Solid-State Circuits, Vol. 34, No. 11, November 1999
AT		

Examiner:	Date Considered:
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.